



**Underwriters
Laboratories**

Test report No. : 31CE0169-HO-02-B-R1
Page : 1 of 49
Issued date : February 23, 2011
Revised date : February 25, 2011
FCC ID : VPYLBSY

RADIO TEST REPORT

Test Report No. : 31CE0169-HO-02-B-R1

Applicant : **Murata Manufacturing Co., Ltd.**

Type of Equipment : **Communication Module**

Model No. : **LBEE69QSYC**

FCC ID : **VPYLBSY**

Test regulation : **FCC Part 15 Subpart C: 2010**

Test Result : **Complied**

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This report is a revised version of 31CE0169-HO-02-B. 31CE0169-HO-02-B is replaced with this report.

Date of test:

February 14 to 17, 2011

**Representative
test engineer:**

T. Shimada

Takumi Shimada
Engineer of WiSE Japan,
UL Verification Service

Approved by:

T. Hatakeda

Takahiro Hatakeda
Leader of WiSE Japan,
UL Verification Service

NVLAP[®]

NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
<http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

MF058b (12.01.11)

CONTENTS	PAGE
SECTION 1: Customer information.....	3
SECTION 2: Equipment under test (E.U.T.).....	3
SECTION 3: Test specification, procedures & results.....	4
SECTION 4: Operation of E.U.T. during testing.....	7
SECTION 5: Conducted Emission.....	9
SECTION 6: Radiated Spurious Emission	10
SECTION 7: Antenna Terminal Conducted Tests.....	11
APPENDIX 1: Photographs of test setup	12
Conducted Emission.....	12
Radiated Spurious Emission.....	13
Worst Case Position	14
APPENDIX 2: Data of EMI test.....	15
Conducted Emission.....	15
20dB Bandwidth and Carrier Frequency Separation.....	20
Number of Hopping Frequency.....	23
Dwell time	25
Maximum Peak Output Power	28
Radiated Spurious Emission.....	29
Conducted Spurious Emission.....	37
Conducted Emission Band Edge compliance.....	44
99% Occupied Bandwidth.....	46
APPENDIX 3: Test instruments	48

SECTION 1: Customer information

Company Name : Murata Manufacturing Co., Ltd.
Address : 10-1, Higashikotari 1-chome, Nagaokakyo-shi, Kyoto 617-8555 Japan
Telephone Number : +81-75-955-7059
Facsimile Number : +81-75-955-7098
Contact Person : Takaharu Kawakatsu

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Communication Module
Model No. : LBEE69QSYC
Serial No. : Refer to Section 4, Clause 4.2
Rating : DC1.8, 3.3V
Receipt Date of Sample : January 17, 2011
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

General Specification

Clock frequency(ies) in the system : 26MHz (WLAN), 38.4MHz (Bluetooth)
Operating temperature range : -20 to +75 deg. C

Radio Specification

WLAN 11b/g/n-20

Radio Type : Transceiver
Frequency of Operation : 2412-2462MHz
Modulation : 11b: DSSS, 11g/n-20: OFDM
Power Supply (radio part input) : DC1.8, 3.3V
Antenna type : Inverted F antenna
Antenna Gain : 3.05dBi

*For WLAN11b/g/n-20 part, see Test Report No. 31CE0169-HO-02-A-R1 issued by UL Japan, Inc.

Bluetooth

Radio Type : Transceiver
Frequency of Operation : 2402-2480MHz
Modulation : FHSS
Power Supply (radio part input) : DC3.3V
Antenna type : Inverted F antenna
Antenna Gain : 3.05dBi

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2010, final revised on December 6, 2010 and effective January 5, 2011

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators Section 15.207 Conducted limits Section 15.247 Operation within the bands 902-928MHz, 2400-2483.5MHz, and 5725-5850MHz

3.2 Procedures and results

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements IC: RSS-Gen 7.2.4	FCC: Section 15.207 IC: RSS-Gen 7.2.4	QP 25.3dB, 10.13610MHz, L AV 16.4dB, 10.13610MHz, L	Complied	-
Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) IC: RSS-210 A8.1 (b)		Complied	Conducted
20dB Bandwidth	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) IC: RSS-210 A8.1 (a)		-	Conducted
Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) IC: RSS-210 A8.1 (d)	See data.	Complied	Conducted
Dwell time	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) IC: RSS-210 A8.1 (d)		Complied	Conducted
Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.8	FCC: Section15.247(a)(b)(1) IC: RSS-210 A8.4 (2)		Complied	Conducted
Spurious Emission & Band Edge Compliance	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.9	FCC: Section15.247(d) IC: RSS-210 A8.5 RSS-Gen 7.2.3	6.7dB 2400.000MHz, AV, Vert.	Complied	Conducted/ Radiated

Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15.

* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

FCC 15.31 (e)

The stable voltage (DC1.8, 3.3V) is constantly provided with the EUT through the regulator installed in the end product. Therefore, the EUT complies with the requirement.

FCC Part 15.203/212 Antenna requirement

It is impossible for end users to replace the antenna, because it is soldered on the circuit board. Therefore, the equipment complies with the antenna requirement of Section 15.203/212.

3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	-	Conducted
Receiver Spurious Emission	IC: RSS-Gen 4.10	IC: RSS-Gen 6	9.0dB 2442.500MHz, AV, Hori.	Complied	Radiated

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi- anechoic chamber)	Conducted emission (+dB)	
	150kHz-30MHz	
No.1	3.1dB	
No.2	3.3dB	
No.3	3.7dB	
No.4	3.2dB	

Test room (semi- anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	3.5dB	5.1dB	5.2dB	4.8dB	5.1dB	4.4dB	4.3dB
No.2	4.0dB	5.1dB	5.2dB	4.8dB	5.0dB	4.3dB	4.2dB
No.3	4.2dB	4.7dB	5.2dB	4.8dB	5.0dB	4.5dB	4.2dB
No.4	4.0dB	5.0dB	5.1dB	4.8dB	5.0dB	5.1dB	4.2dB

*3m/1m/0.5m = Measurement distance

Power meter (+dB)	
Below 1GHz	Above 1GHz
1.0dB	1.0dB

Antenna terminal conducted emission and Power density (+dB)			Antenna terminal conducted emission (+dB)		Channel power (+dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz	
1.0dB	1.1dB	2.7dB	3.2dB	3.3dB	1.5dB

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test

The data listed in this test report has enough margin, more than the site margin.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Faxsimile : +81 596 24 8124

3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9
 Receiving (Rx)
 Inquiry

Details of Operating Mode(s)

Test Item	Mode	Tested frequency
Conducted Emission, Spurious Emission (Conducted/Radiated)	Tx (Hopping off) DH5, 3DH5	2402MHz 2441MHz 2480MHz
	Rx	2441MHz
Carrier Frequency Separation	Tx (Hopping on) DH5, 3DH5 Inquiry	2402MHz 2441MHz 2480MHz
20dB Bandwidth	Tx (Hopping off) DH5, 3DH5 Inquiry	2402MHz 2441MHz 2480MHz
Number of Hopping Frequency	Tx (Hopping on) DH5, 3DH5 Inquiry	-
Dwell time	Tx (Hopping on), -DH1, DH3, DH5 -3DH1, 3DH3, 3DH5 Inquiry	-
Maximum Peak Output Power	Tx (Hopping off) DH5, 3DH5 Inquiry	2402MHz 2441MHz 2480MHz
Band Edge Compliance (Conducted)	Tx DH5, 3DH5 -Hopping on -Hopping off	2402MHz 2480MHz
99% Occupied Bandwidth	Tx DH5, 3DH5 -Hopping on -Hopping off	2402MHz 2441MHz 2480MHz

*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)

*EUT has the power settings by the software as follows;

Power settings: BDR: Ext.=0, Int.=47
 EDR: Ext.=0, Int.=53

Software: CSR BlueSuite BlueTest Version 2.2.0.0
 CSR BlueSuite BtCliCtrl Version 2.2.0.0 (Inquiry mode only)

*This setting of software is the worst case.

Any conditions under the normal use do not exceed the condition of setting.

In addition, end users cannot change the settings of the output power of the product.

UL Japan, Inc.

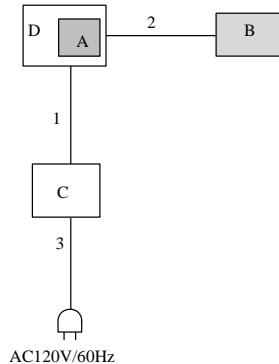
Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

4.2 Configuration and peripherals



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Communication Module	LBEE69QSYC	001	Murata Manufacturing Co., Ltd.	EUT
B	Antenna	WDAN-F1SN1001-DF-REF	4	Murata Manufacturing Co., Ltd.	EUT
C	DC Power Supply *1)	PW18-1.3AT	08016530	KENWOOD	-
D	Jig Board	-	-	Murata Manufacturing Co., Ltd.	-

*1) Used for Conducted Emission test only

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	DC Cable	1.6	Unshielded	Unshielded	-
2	Antenna Cable	0.5	Unshielded	Unshielded	-
3	AC Cable *1)	2.4	Unshielded	Unshielded	-

*1) Used for Conducted Emission test only

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 0.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber. The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector	: QP and AV
Measurement range	: 0.15-30MHz
Test data	: APPENDIX
Test result	: Pass

SECTION 6: Radiated Spurious Emission

Test Procedure

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 0.8m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below:

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

Frequency	Below 1GHz	Above 1GHz	
Instrument used	Test Receiver	Spectrum Analyzer	
Detector	QP	PK	AV
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz VBW: 3MHz	RBW: 1MHz VBW: 10Hz or RBW: 1MHz VBW: 270Hz *1)
Test Distance	3m	3m (below 10GHz), 1m*2) (above 10GHz)	

*1) Used for the band edge of the carrier and the harmonics that can be measured. The VBW is based on the inverse of the duty cycle (see Appendix).

*2) Distance Factor: $20 \times \log (3.0m/1.0m) = 9.5dB$

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of module and antenna to see the position of maximum noise, and the test was made at the position that has the maximum noise.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 30M-25GHz
Test data : APPENDIX
Test result : Pass

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

SECTION 7: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	3MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	5MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	1MHz	3MHz	As necessary capture the entire dwell time per hopping channel	Peak	Max Hold	Spectrum Analyzer
Conducted Spurious Emission	Less or equal to 5GHz (Range: 30MHz-25GHz)	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Conducted Spurious Emission Band Edge compliance	20MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : APPENDIX
Test result : Pass